

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination DIERICKX ET AL.	
		Examiner Deborah Yee	Art Unit 1742	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-RÉ28,523	08-1975	Hill et al.	420/8
	C	US-			
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	M	US-			

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**NON-PATENT DOCUMENTS**

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